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Application/Control No.	Applicant(s)/Patent unde Reexamination	r
09/966,897	KAKANI ET AL.	
Examiner	Art Unit	
Thien D. Tran	2665	

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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	235	11/23/2005	ΤΤ
	229	11/23/2005	`TT

SEARCH NOT (INCLUDING SEARCH		)
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EAST (USPGPUB, USOCR, EPO, DERWENT, USPAT) 370/229, 230, 235, 235.1, 236	11/23/2005	тт
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